Search Notes

Application/Control N	Applicant(s)/Patent under Reexamination	
09/663,811	HACHERL ET AL.	
Examiner	Art Unit	
Shin-Hon Chen	2131	_

SEARCHED					
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
726	27-30	11/15/2006	S.C.	
709	229	11/15/2006	S.C.	
726	2-4	11/15/2006	S.C.	
707/201,204		11/15/2006	S.C.	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
USPAT, PGPUB, DERWENT, JPO, EPO (BRS search)	11/15/2006	S.C.		
11.2847				